

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Aug. 04, 2013

Expected First Date Code of Changed Product :1330

Description of Change (From) :

7-lead and 8-lead MDIP packages manufactured at Vigilant Technology Company limited.

	From
Site/ Location	Vigilant Technology Company Limited Thailand
Leadframe	Copper
Die Attach	Ablebond 2200D
Wire	Au 1.0mil
Mold Compound	Nitto GE-800 (Green)
Plating	Pure Sn

Description of Change (To) :

7-lead and 8-lead MDIP packages manufactured at Vigilant Technology Company Limited and Automated Technology Inc (ATEC), Philippines.

	Change To	Change To
Site/ Location	Vigilant Technology Company Limited Thailand	Automated Technology Inc (ATEC) Philippines
Leadframe	Copper	Copper
Die Attach	Ablebond 2200D	Ablebond 84-1LMISR4
Wire	1 mil Au	Au 1.0mil
Mold Compound	Nitto GE-800 (Green)	Nitto GE-800 (Green)
Plating	Pure Tin	Pure Tin

Reason for Change:

To provide for supply continuity for MDIP 7/8L package products.

Affected Product(s):

DNP013	FS117N	FSB117CHN
FSB117HNY	FSB117HNY_F116	FSB127AHN
FSB127HNY	FSB127HNY_SN00271	FSB147HNY
FSBH0170ANY	FSBH0170NY	FSBH0170NY_F116
FSBH0170WNY	FSBH0270ANY	FSBH0270NY
FSBH0270NY_F116	FSBH0270WNY	FSBH0370NY
FSBH0370NY_F116	FSBH0F70ANY	FSBH0F70ANY_F116
FSBH0F70WANY	FSD106LG	FSD146MRBN
FSD156MRBN	FSDH0265RN	FSDH321
FSDL0165RN	FSDL0165RN_SN00228	FSDL321
FSDM0265RNB	FSDM0365RNB	FSDM311
FSDM311A	FSEM0265RNB	FSEM0365RNB
FSEM311	FSEM311Z	FSFM260N
FSFM300N	FSGM300N	FSL106HR
FSL106MR	FSL116HR	FSL116LR
FSL117MRIN	FSL126HR	FSL126MR
FSL126MRG	FSL136HR	FSL136MR
FSL136MRG	FSL136MRS	FSL137HNY
FSL137MRIN	FSL146MRBN	FSL156MRBN
FSL156MRIN	FSL206MRBN	FSL206MRN
FSL206MRN1	FSL306LRN	FSLH137NY
FSQ0165RN	FSQ0170RNA	FSQ0265RN
FSQ0270RNA	FSQ0270RNA_SN00229	FSQ0365RN
FSQ0370RNA	FSQ100	FSQ110
FSQ211	FSQ321	

Qualification Plan	Device	Package	Process	No. of Lots
Q20130014	FSGM300N	8DIP	FS50D + Unisensefet	3

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Operating Life	125C, Vcc=22V, Vds=50V, VSTR=520V	JESD22-A108	1000 hrs	0/231
Temperature Humidity Biased Test	85C, 85%RH, Vcc=26V, Vdd=100V	JESD22-A101	1000 hrs	0/231
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/231
High Temperature Reverse Bias	125C, 80% VDS	JESD22-A108	1000 hrs	0/231
Temperature Cycle with Precon	-65C, 150C	JESD22-A104	500 cycles	0/231

Qualification Plan	Device	Package	Process	No. of Lots
Q20130014	FSQ0370RNA	8DIP	SDG4 +Q-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Operating Life	125C, Vcc=17V, Vds=50V, VSTR=520V	JESD22-A108	1000 hrs	0/77
Temperature Humidity Biased Test	85C, 85%RH, Vcc=20V, Vdd=100V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	125C, 80% VDS	JESD22-A108	1000 hrs	0/77
Temperature Cycle with Precon	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130014	FSQ0265RN	8DIP	SDG4D + A-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Operating Life	125C, Vcc=20V, Vds=50V, VSTR=520V	JESD22-A108	1000 hrs	0/77
Temperature Humidity Biased Test	85C, 85%RH, Vcc=20V, Vdd=100V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	125C, 80% VDS	JESD22-A108	1000 hrs	0/77
Temperature Cycle with Precon	-65C, 150C	JESD22-A104	500 cycles	0/77